

<b>Notice of References Cited</b>		Application/Control No. 10/634,414	Applicant(s)/Patent Under Reexamination KUZAWINSKI ET AL	
		Examiner Alexander O Williams	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,489,682 B1	12-2002	Yeh et al.	257/738
	B	US-6,359,341 B1	03-2002	Huang et al.	257/778
	C	US-6,790,760 B1	09-2004	Cohn et al.	438/613
	D	US-6,770,963	08-2004	Wú, Ping	257/691
	E	US-2004/0124545 A1	07-2004	Wang	257/784
	F	US-6,812,580 B1	11-2004	Wenzel et al.	257/784
	G	US-6,756,665 B1	06-2004	Chang, Nai-Shung	257/691
	H	US-6,703,698 B2	03-2004	Huang et al.	257/678
	I	US-6,582,979 B2	06-2003	Cocciali et al.	438/25
	J	US-2003/0179549 A1	09-2003	Zhong et al.	361/707
	K	US-5,741,729	04-1998	Selna, Erich	438/125
	L	US-6,541,854	04-2003	Huang et al.	257/707
	M	US-6,465,882 B1	10-2002	Cohn et al.	257/691

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	8-8359	01-1996	Japan	Ochi et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.